### QUADRUPLE 2-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

APRIL 1985 - REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

### description

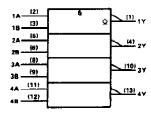
These devices contain four independent 2-input NAND gates. The open-collector outputs require pull-up resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher VOH levels.

The SN5401 and SN54LS01 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN7401 and SN74LS01 are characterized for operation from 0°C to 70°C.

### **FUNCTION TABLE (each gate)**

INP	UTS	OUTPUT
Α	В	Υ
Н	н	L
L	X	[ н
×	L	н

### logic symbol†



<sup>&</sup>lt;sup>†</sup>This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

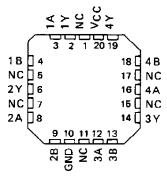
SN5401 J PACKAGE
SN54LS01 J OR W PACKAGE
SN7401 N PACKAGE
SN74LS01 D OR N PACKAGE
(TOP VIEW)

1Y	Пı	U14□ V <sub>CC</sub>
1A	$\square^2$	13 4 Y
1B	□3	12 🗆 4 B
2Y	□4	11 AA
2A	₫5	10 3Y
2B	□6	9∏ 3B
GND	口。	8 <b>∐ 3A</b>

# SN5401 . . , W PACKAGE (TOP VIEW)

1 A	ďι	U 14] 4 Y
1 B	<b>2</b>	13🗀 4 B
1 Y	□3	12 4A
V c c	□4	סאם ⊈יו
2 Y	□5	10 <b>□ 3 B</b>
2A	<b>[</b> 6	9 🗖 3 A
2 B	口7	8 🗖 3 Ƴ

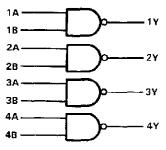
# SN54LS01 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

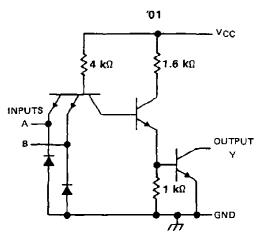
## QUADRUPLE 2-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

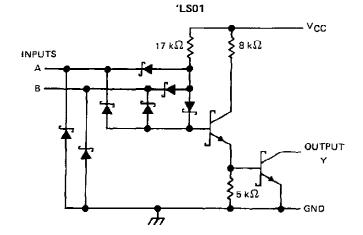
### logic diagram (positive logic)



positive logic;  $Y = \overline{A \cdot B}$  or  $Y = \overline{A} + \overline{B}$ 

### schematics (each gate)





Resistor values shown are nominal.

# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1): '0	01, 'LS01 7	٧
	5.5	
'L\$01	. ,	٧
Off-state output voltage		٧
Operating free-air temperature range:	SN54' ~55°C to 125°	,C
	SN74' 0°C to 70°	,C
Storage temperature range	65°C to 150°	,C

NOTE 1: Voltage values are with respect to network ground terminals.

# SN5401, SN7401 QUADRUPLE 2-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

### recommended operating conditions

			SN5401			SN7401		
		MIN	NOM	MAX	MIN	NOM	МАХ	UNIT
vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage	2		-	2			٧
VIL	Low-level input voltage			0.8			8.0	V
۷он	High-level output voltage			5.5		_	5,5	ν
IOL	Low-level output current		-	16			16	mΑ
Тд	Operating free-air temperature	- 55		125	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADARETED	TEST CONDITIONS <sup>†</sup>	SN5401	SN7401	
PARAMETER	TEST CONDITIONS	MIN TYP# MAX	MIN TYP‡ MAX	UNIT
Vik	V <sub>CC</sub> = MIN, I <sub>I</sub> = -12 mA	-1.5	-1.5	V
	VCC = MIN, VIL = 0.8 V, VOH = 5.5 V		0.25	- ^
ЮН	VCC = MIN, VIL = 0.7 V, VOH = 5.5 V	0.25		mΑ
VOL	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, I <sub>OL</sub> = 16 mA	0.2 0.4	0.2 0.4	V
4	VCC = MAX, VI = 5.5 V	1	1	mΑ
lн	$V_{CC} = MAX$ , $V_{I} = 2.4 \text{ V}$	40	40	μА
l <sub>IL</sub>	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4 V	-1.6	-1.6	mΑ
<b>І</b> ссн	$V_{CC} = MAX, V_1 = 0$	4 8	4 8	mΑ
<sup>I</sup> CCL	$V_{CC} = MAX$ , $V_{\parallel} = 4.5 \text{ V}$	12 22	12 22	mA

<sup>&</sup>lt;sup>†</sup>For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

## switching characteristics, VCC = 5 V, TA = 25°C (see note 2)

PARAMETER	FROM (INPUT)	<b>T</b> O (OUTPUT)	TEST CONDITIONS		MIN TY	MAX	UNIT
<sup>T</sup> PLH	A or B	V	RL=4kΩ,	C <sub>L</sub> = 15 pF	35	55	ns
<sup>t</sup> PHL	700	' 1	R <sub>L</sub> = 400 Ω,	CL = 15 pF		15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

 $<sup>^{\</sup>ddagger}$ All typical values are at  $V_{CC}$  = 5 V,  $T_{A}$  = 25 °C.

# SN54LS01, SN74LS01 QUADRUPLE 2-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

### recommended operating conditions

		SN54LS	.\$01 SN74L\$01		301		
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC Supply voltage	4,5	5	5.5	4.75	5	5.25	V
V <sub>IH</sub> High-level input voltage	2			2			V
V <sub>IL</sub> Low-level input voltage		-	0.7			0.8	V
VOH High-level output voltage			5.5			5.5	V
OL Low-level output current			4			8	mА
T <sub>A</sub> Operating free-air temperature	- 55		125	0		70	°c

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST COMPLETIONS *		SN54LS01			SN74LS01				
PARAMETER		TEST CONDITIONS†		MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
VIK	V <sub>CC</sub> - MIN,	I <sub>I</sub> = ~ 18 mA				- 1.5			- 1.5	V
10Н	VCC = MIN,	VIL = MAX,	V <sub>OH</sub> = 5.5 V			0.1			0.1	mA
14	V <sub>CC</sub> = MIN,	V <sub>IH</sub> = 2 V,	IOL = 4 mA		0.25	0.4		0.25	0.4	
Vol	V <sub>CC</sub> = MIN,	V <sub>IH</sub> = 2 V,	IOL - 8 mA					0.35	0.5	\
ij	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 7 V				0.1			0.1	mA
Ìтн	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 2.7 V				20			20	μА
li L	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 0.4 V				- 0.4			- 0.4	mA
ГССН	VCC = MAX.	V <sub>I</sub> = 0			0.8	1.6		0.8	1.6	mΑ
1 <sub>CCL</sub>	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 4.5 V			2.4	4.4		2.4	4.4	mA

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

# switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MłN	TYP	MAX	UNIT
tPLH .	A or B	·	B <sub>1</sub> = 2kO	C <sub>L</sub> = 15 pF		17	32	ns
<sup>‡</sup> PHL	70.0		R <sub>L</sub> = 2 kΩ,	C[ - 15 pr		15	28	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

<sup>‡</sup> All typical values are at  $V_{CC}$  = 5 V,  $T_A$  = 25°C.

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